



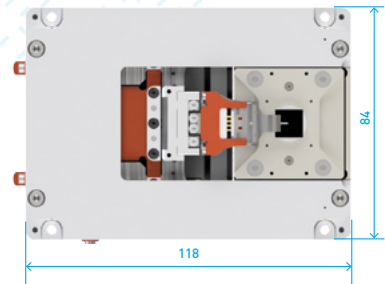
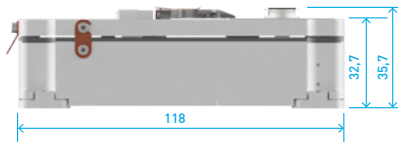
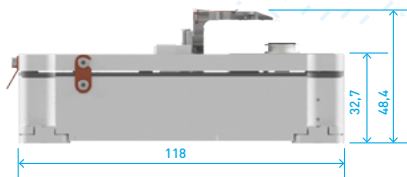
Technical Specification

Environmental

Operating temperature	+10 °C to +35 °C
Operating pressure	10 ⁻⁵ Pa to 10 ⁵ Pa
Dry environment only	

Mechanical

Overall dimensions	118 mm × 84 mm × 35,7 – 48,4 mm
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Weight	460 g
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Maximal scanned sample area	21 mm × 11 mm × 8 mm
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Coarse approach	True orthogonal positioning
	Calibrated, pre-stressed linear ball bearings
	Open Loop and Closed Loop option

Coarse approach	Self-locking
	Speed > 2 mm/s
	Travel range XYZ: 21 mm × 12 mm × 12 mm

Scanning unit	Open Loop / Closed Loop option
	Scan range in open loop XYZ (±10%): 100 μm × 100 μm × 20 μm
	Scan range in closed loop XYZ: 80 μm × 80 μm × 16 μm

Scanning unit	Resolution XYZ: 0.2 nm × 0.2 nm × 0.04 nm
	Based on multi-layer, low-voltage piezoelectric transducer

Scanning unit	Solid state flexure guide system
	Universal acceptor for different probes

Scanning unit	Five standard probe holders
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Fast and easy probe exchange	
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Sample holder for standard SEM stubs (Ø12.7 mm with Ø3.2 mm and up to 6 mm long pin)	Two additional positions for SEM/FIB imaging/machining (not to be measured by AFM)
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Operation and control system

Modes of operation	Topography and surface roughness, Energy dissipation (tapping mode), FMM (contact mode), F-z curves, nanoindentation, C-AFM, C-CPEM, KPFM, PFM, I-V spectroscopy, STM, MFM
Probes	Akiyama probe, Tuning-fork based probes, Piezoresistive probes, NenoProbes, etc.
Input channels could be used in feedback-loop	
Probe signal output / monitor	
External probe excitation	
All necessary connections for using external PLL	
Ethernet connection to the control PC	
110 VAC / 230 VAC operation, 200 W	

Software

Web based user interface	
Easy for new users, flexible for experts	
User accounts	Every user has an account Accounts individually configurable – layout, parameters, complexity,...
Remote access to the user data, download of data from control PC to the local workstation	
Remote experiment control via eg. tablet, smartphone	
Integrated data post-processing, analysis, export, etc.	



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